

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of: Sebastien KERDILES et al.

Confirmation No.

Application No.:

Group Art Unit:

Filing Date:

Examiner:

For: TOOLS AND METHODS FOR DISUNITING  
SEMICONDUCTOR WAFERS

Atty. Docket No.: 4717-9100

**INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, Virginia 22313-1450

Sir:

Pursuant to applicants' duty of disclosure under 37 C.F.R. 1.56, enclosed are copies of twelve (12) references for the Examiner's review and consideration. These references are listed on the enclosed Form PTO-1449.

These references were cited in the European Search Report a copy of which is enclosed. It is respectfully requested that these references be made of record in this application by the Examiner's completion and return of the PTO Form 1449.

No fee or certification is believed to be due for this submission since the references are being submitted concurrent with the filing of this application. Should any fees be required, however, please charge such fees to **Winston & Strawn** Deposit Account No. 50-1814.

Date: \_\_\_\_\_

12/12/63

Respectfully submitted,



Allan A. Fanucci (Reg. No. 30,256)

**WINSTON & STRAWN LLP**  
**CUSTOMER NO. 28765**  
(212) 294-3311

Enclosures

<b>LIST OF REFERENCES CITED BY APPLICANT</b> <i>(Use several sheets if necessary)</i>					ATTY. DOCKET NO.:		APPLICATION NO.:	
					4717-9100			
					APPLICANT:			
					Sebastien KERDILES et al.			
					FILING DATE:		GROUP:	
<b>U.S. PATENT DOCUMENTS</b>								
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	AA	5,133,824	7/1992	Huberts et al.	156	344		
	AB	5,374,564	12/1994	Bruel	437	24		
	AC	5,447,596	9/1995	Hayase	156	584		
	AD	6,215,643 B1	4/2001	Nagasaki	361	234		
	AE	6,351,367 B1	2/2002	Mogi et al.	361	234		
	AF	6,468,879	10/2002	Lamure et al.	438	458		
<b>FOREIGN PATENT DOCUMENTS</b>								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AG	0 432 832 A1	6/1991	Europe			X	
	AH	0 989 593 A2	3/2000	Europe			X	
	AI	2, 572 216 (with English Abstract)	4/1986	France			X	
	AJ	GB 2 124 547	2/1984	United Kingdom			X	
	AK	JP 60196644 (with English Abstract)	10/1995	Japan			X	
	AL	WO 00/26000	5/2000	PCT			X	
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)</b>								
	AM							
	AN							
	AO							
<b>EXAMINER</b>					<b>DATE CONSIDERED</b>			
<b>*EXAMINER:</b> Initial if reference considered, whether or not citation is in conformance with <b>MPEP 609</b> ; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								